PASCARI

ENTERPRISE X-SERIES

High-Endurance PCIe Gen5 Enterprise SSD for Write-Intensive Applications

PASCARI X200Z

Sequential Read

Up to 14,800 MB/s

Sequential Write

Up to 9,500 MB/s

Random Read

Up to 3,100K IOPS

Random Write

Up to 950K IOPS

Interface

PCIe 5.0 2x2 (Dual port)

Capacity

Up to 3.2TB

Form Factor

U.2

DWPD

60

Product Features

- NVMe 2.0
- 128 Namespaces
- Power Loss Protection (PLP)
- ISE support
- AES-XTS 256-bit Encryption
- Data Integrity and Protection
- End-to-End Data Path Protection
- Metadata Protection
- SECDED
- Sanitize
- NVMe-MI (Management Interface)
- SMBus

PHISON

Solution - X200Z

Form Factor U.2			
Capacity[1]	800GB	1.6TB	3.2TB
Interface	PCIe 5.0 2x2	PCIe 5.0 2x2	PCIe 5.0 2x2
NVMe	2.0	2.0	2.0
NAND Flash	3D TLC	3D TLC	3D TLC
Performance[2,3,4]			
Sequential Read (MB/s)	14,800	14,800	14,800
Sequential Write (MB/s)	9,500	9,500	9,500
4K Random Read (IOPS)	3,100K	3,100K	2,800K
4K Random Write (IOPS)	950K	950K	950K
Random Read Latency (Typ., µs)	45	45	45
Random Write Latency (Typ., µs)	10	10	10
Power Consumption [5]			
Active (W)	18	20	21
Idle (W)	5	5	5
Endurance/Reliability			
DWPD[6]	60	60	60
UBER	< 1 sector per 10^{18} bits read	< 1 sector per 10^{18} bits read	< 1 sector per 10^{18} bits read
MTBF (million hours)	2.5	2.5	2.5
Limited Warranty (years)	5	5	5
Temperature			
Operating Temp. (°C)	0 - 70	0 - 70	0 - 70
Non-Operating Temp. (°C)	-40 - 85	-40 - 85	-40 - 85
Physical Dimension			
Length (mm)	100.10	100.10	100.10
Width (mm)	69.85	69.85	69.85
Height (mm)	15.00	15.00	15.00
Weight (g)	199	201	168
Part Number			
Dual Port ISE FW	XX208H02800GZ3 14T0900	XX208H021T60Z3 18T1900	XX208H023T20Z31 16T300

(1) 1 TB = 10^{12} bytes.
(2) Sequential Performance is based on FIO on Linux, 512KB data size, with QD=32, 1 job.
(3) Random Performance is based on FIO on Linux, 4KB data size, QD=128, 8 jobs.
(4) Latency is measured with random workloads based on FIO on Linux, 4KB data size, QD=1, 1 job.
(5) Power consumption (average RMS) is measured during the sequential read/write and random read/write operations performed by iometer with the conditions described in (2) and (3).
(6) The results of DWPD are obtained in compliance with JESD219A standards.

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